

**Notice of References Cited**

Application/Control No.

10/076,672

Applicant(s)/Patent Under  
Reexamination  
TOMONO ET AL.

Examiner

David A. Zarneke

Art Unit

2827

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6028353	02-2000	Nakano et al.	257/701
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Takaya et al., US Patent Application Publication 2002/0009577 A1, 1/24/02.
	V	Kitamura, US Patent Application Publication 2002/0093415 A1, 7/18/02.
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	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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